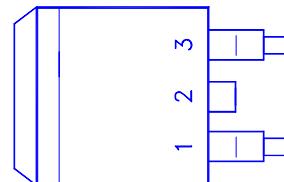
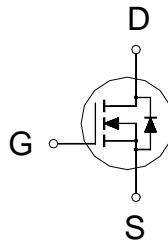


NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P70N02LS
TO-263 (D²PAK)
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
25	7mΩ	70A


1. GATE
2. DRAIN
3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	$V_{GS} \pm$	20	V
Continuous Drain Current	I_D	70	A
		45	
Pulsed Drain Current ¹	I_{DM}	170	
Avalanche Current	I_{AR}	60	
Avalanche Energy	E_{AS}	140	mJ
Repetitive Avalanche Energy ²	E_{AR}	5.6	
Power Dissipation	P_D	65	W
		38	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C
Lead Temperature (1/16" from case for 10 sec.)	T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.3	
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W
Case-to-Heatsink	$R_{\theta CS}$	0.6		

¹Pulse width limited by maximum junction temperature.²Duty cycle ≤ 1%**ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER SY	MBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	YP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.1.5		3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			±250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			25	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			250	

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On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 10V, V _{GS} = 10V	70			A
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 30A		7	9	mΩ
		V _{GS} = 7V, I _D = 24A		8	10	
Forward Transconductance ¹	g _{fs} V	V _{DS} = 15V, I _D = 30A		16		S

DYNAMIC

Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 15V, f = 1MHz	2700			pF
Output Capacitance	C _{oss}		500			
Reverse Transfer Capacitance	C _{rss}		200			
Total Gate Charge ²	Q _g	V _{DS} = 0.5V _{(BR)DSS} , V _{GS} = 10V, I _D = 35A	25			nC
Gate-Source Charge ²	Q _{gs}		7			
Gate-Drain Charge ²	Q _{gd}		11			
Turn-On Delay Time ²	t _{d(on)}		7			
Rise Time ²	t _r	V _{DS} = 15V, R _L = 1Ω I _D ≈ 30A, V _{GS} = 10V, R _{GS} = 2.5Ω	7			nS
Turn-Off Delay Time ²	t _{d(off)}		24			
Fall Time ²	t _f		6			

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_C = 25 °C)

Continuous Current	I _S	V _{GS} = 0V, I _F = I _S , V _{DS} = 0V		70		A
Pulsed Current ³ I	SM				170	
Forward Voltage ¹ V	SD I				1.3	V
Reverse Recovery Time	t _{rr}	I _F = I _S , dI _F /dt = 100A / μS	37			nS
Peak Reverse Recovery Current	I _{RM(REC)}		200			A
Reverse Recovery Charge	Q _{rr}		0.043			μC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH “P70N02LS”, DATE CODE or LOT #**

NIKO-SEM**N-Channel Logic Level Enhancement
Mode Field Effect Transistor****P70N02LS
TO-263 (D²PAK)****TO-263 (D²PAK) MECHANICAL DATA**

Dimension	mm			Dimension	mm		
	Min. T	yp.	Max.		Min. T	yp.	Max.
A	14.5	15	15.8	H	1.0	1.5	1.8
B	4.2		4.7 9.8				10.3
C	1.20		1.35	J	6.5		
D	2.8			K	1.5		
E	0.3	0.4	0.5 L 0.7				1.4
F	-0.102		0.203	M	4.83 5.08 5.33		
G 8.5		9	9.5	N			

